# Low Skew CMOS PLL Clock Driver

# MC88915

The MC88915 Clock Driver utilizes phase—locked loop technology to lock its low skew outputs' frequency and phase onto an input reference clock. It is designed to provide clock distribution for high performance PC's and workstations.

The PLL allows the high current, low skew outputs to lock onto a single clock input and distribute it with essentially zero delay to multiple components on a board. The PLL also allows the MC88915 to multiply a low frequency input clock and distribute it locally at a higher (2X) system frequency. Multiple 88915's can lock onto a single reference clock, which is ideal for applications when a central system clock must be distributed synchronously to multiple boards (see Figure 7).

Five "Q" outputs (QO-Q4) are provided with less than 500 ps skew between their rising edges. The  $\overline{Q5}$  output is inverted (180° phase shift) from the "Q" outputs. The 2X\_Q output runs at twice the "Q" output frequency, while the Q/2 runs at 1/2 the "Q" frequency.

The VCO is designed to run optimally between 20 MHz and the 2X\_Q Fmax specification. The wiring diagrams in Figure 5 detail the different feedback configurations which create specific input/output frequency relationships. Possible frequency ratios of the "Q" outputs to the SYNC input are 2:1. 1:1, and 1:2.

The FREQ\_SEL pin provides one bit programmable divide—by in the feedback path of the PLL. It selects between divide—by—1 and divide—by—2 of the VCO before its signal reaches the internal clock distribution section of the chip (see the block diagram on page 2). In most applications FREQ\_SEL should be held high (+1). If a low frequency reference clock input is used, holding FREQ\_SEL low (+2) will allow the VCO to run in its optimal range (>20 MHz).

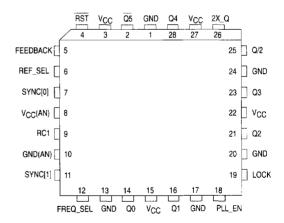
In normal phase–locked operation the PLL\_EN pin is held high. Pulling the PLL\_EN pin low disables the VCO and puts the 88915 in a static "test mode". In this mode there is no frequency limitation on the input clock, which is necessary for a low frequency board test environment. The second SYNC input can be used as a test clock input to further simplify board–level testing (see detailed description on page 11).

A lock indicator output (LOCK) will go high when the loop is in steady–state phase and frequency lock. The LOCK output will go low if phase–lock is lost or when the PLL\_EN pin is low. Under certain conditions the lock output may remain low, even though the part is phase–locked. Therefore the LOCK output signal should not be used to drive any active circuitry; it should be used for passive monitoring or evaluation purposes only.

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### **Features**

- Five Outputs (QO-Q4) with Output-Output Skew < 500 ps each being phase and frequency locked to the SYNC input
- The phase variation from part-to-part between the SYNC and FEEDBACK inputs is less than 550 ps (derived from the tpp specification, which defines the part-to-part skew)
- Input/Output phase-locked frequency ratios of 1:2, 1:1, and 2:1 are available
- Input frequency range from 5MHz 2X\_Q FMAX spec
- Additional outputs available at 2X and +2 the system "Q" frequency. Also a Q (180° phase shift) output available
- All outputs have ±36 mA drive (equal high and low) at CMOS levels, and can drive either CMOS or TTL inputs.
   All inputs are TTL-level compatible
- Test Mode pin (PLL\_EN) provided for low frequency testing. Two selectable CLOCK inputs for test or redundancy purposes

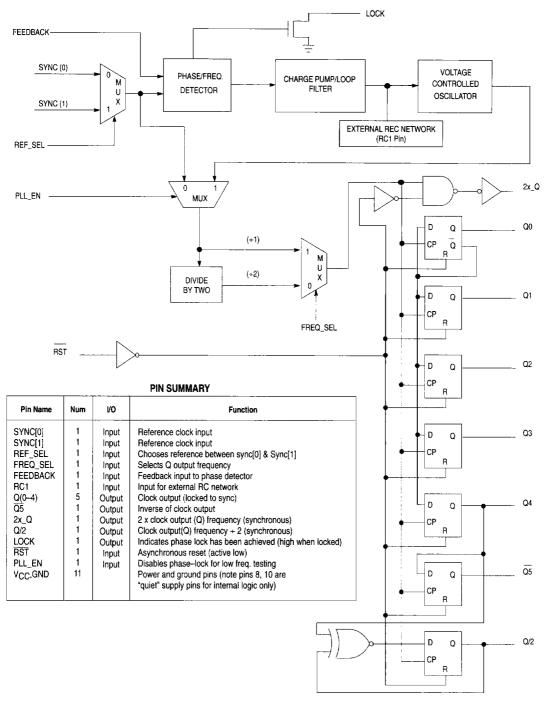


28-Lead Pinout (Top View)

FN SUFFIX PLASTIC PLCC CASE 776-02

### ORDERING INFORMATION

MC88915FN55 PLCC MC88915FN70 PLCC



MC88915 Block Diagram

## DC ELECTRICAL CHARACTERISTICS (Voltages Referenced to GND; TA =0° C to + 70° C, V<sub>CC</sub> = 5.0V ± 5%)

Symbol	Parameter	Test Conditions	V <sub>CC</sub>	Guaranteed Limit	Unit
VIH	Minimum High-Level Input Voltage	V <sub>out</sub> = 0.1 V or V <sub>CC</sub> - 0.1 V	4.75 5.25	2.0 2.0	٧
VIL	Maximum Low-Level Input Voltage	V <sub>out</sub> = 0.1 V or V <sub>CC</sub> - 0.1 V	4.75 5.25	0.8 0.8	٧
Vон	Minimum High-Level Output Voltage	V <sub>in</sub> = V <sub>IH</sub> or V <sub>IL</sub> I <sub>OH</sub> = -36 mA 1	4.75 5.25	4.01 4.51	V
V <sub>OL</sub>	Maximum Low-Level Output Voltage	V <sub>in</sub> = V <sub>IH</sub> or V <sub>IL</sub> I <sub>OL</sub> = 36 mA 1	4.75 5.25	0.44 0.44	٧
lin	Maximum Input Leakage Current	V <sub>I</sub> = V <sub>CC</sub> or GND	5.25	±1.0	μА
<sup>I</sup> CCT	Maximum I <sub>CC</sub> /Input	V <sub>I</sub> = V <sub>CC</sub> - 2.1 V	5.25	1.5 2	mA
lold	Minimum Dynamic Output Current 3	V <sub>OLD</sub> = 1.0V Max	5.25	88	mA
OHD		V <sub>OHD</sub> = 3.85 V Max	5.25	-88	mA
lcc	Maximum Quiescent Supply Current (per Package)	V <sub>I</sub> = V <sub>CC</sub> or GND	5.25	1.0	mA

<sup>1.</sup>  $I_{OL}$  and  $I_{OH}$  are 12mA and –12mA respectively for the LOCK output. 2. The PLL\_EN input pin is not guaranteed to meet this specification.

### **CAPACITANCE AND POWER SPECIFICATIONS**

Symbol	Parameter	Typical Values	Unit	Conditions
CIN	Input Capacitance	4.5	рF	V <sub>CC</sub> = 5.0 V
C <sub>PD</sub>	Power Dissipation Capacitance	40	рF	V <sub>CC</sub> = 5.0 V
PD <sub>1</sub>	Power Dissipation @ 33MHz with 50Ω Thevenin Termination	15 mW/Output 120 mW/Device	mW	V <sub>CC</sub> = 5.0 V T = 25°C
PD <sub>2</sub>	Power Dissipation @ 33MHz with 50Ω Parallel Termination to GND	37.5 mW/Output 300 mW/Device	mW	V <sub>CC</sub> = 5.0 V T = 25° C

### SYNC INPUT TIMING REQUIREMENTS

Symbol	Symbol Parameter		in	Max	Unit
<sup>†</sup> RISE, <sup>†</sup> FALL	Maximum Rise and Fall times, (SYNC Inputs: From 0.8V - 2.0V)			3.0	ns
	Input Clock Period (SYNC Inputs)	FN55	FN70	2007	ns
tCYCLE		36	28.5	2001	115
Duty Cycle	Input Duty Cycle (SYNC Inputs)		50% ±	±25%	

<sup>1.</sup> Information in Fig. 5 and in the "General AC Specification Notes", Note #3 describes this specification and its actual limits depending on the application.

# FREQUENCY SPECIFICATIONS (T<sub>A</sub> =0° C to + 70° C, $V_{CC}$ = 5.0V ±5%, $C_L$ = 50pF)

		Guarantee		
Symbol	Parameter	MC88915FN55	MC88915FN70	Unit
f <sub>max</sub> 1	Maximum Operating Frequency (2X_Q Output)	55	70	MHz
	Maximum Operating Frequency (Q0-Q4,Q5 Output)	27.5	35	MHz

<sup>1.</sup> Maximum Operating Frequency is guaranteed with the part in a phase-locked condition, and all outputs loaded at 50 pF.

<sup>3.</sup> Maximum test duration is 2.0ms, one output loaded at a time.

# AC ELECTRICAL CHARACTERISTICS (T<sub>A</sub> =0° C to +70° C, $V_{CC}$ = 5.0V ±5%, $C_L$ = 50pF)

Symbol	Parameter	Min	Max	Unit
tRISE, tFALL (Outputs)	Rise and Fall Times, all Outputs Into a 50 pF, 500 $\Omega$ Load (Between 0.2VCC and 0.8VCC)	1.0	2.5	ns
tRISE, tFALL 3 (2X_Q Output)	Rise and Fall Time, 2X_Q Output Into a 20 pF Load With Termination specified in note 2 (Between 0.8 V and 2.0 V)	0.5	1.6	ns
<sup>t</sup> Pulse Width <sup>3</sup>	t <sub>Pulse Width</sub> <sup>3</sup> Output Pulse Width (Q0, Q1, Q3, Q4, $\overline{\text{Q5}}$ , Q/2 @V <sub>CC</sub> /2)		0.5t <sub>CYCLE</sub> + 0.5	
(Q0,Q1,Q3,Q4, Q5,Q/2)		tCYCLE = 1/Freq	. at which the "Q"	
		Outputs a	re running	ns
tPulse Width <sup>3</sup> (Q2 only)	Output Pulse Width (Q2 Output @ V <sub>CC</sub> /2)	0.5tCYCLE - 0.6	0.5t <sub>CYCLE</sub> + 0.6	
tPulse Width 3 (2X_Q Output)	Output Pulse Width (2X_Q Output @ 1.5 V) (See AC Note 2)	0.5t <sub>CYCLE</sub> - 0.5	0.5t <sub>CYCLE</sub> + 0.5	ns
tPulse Width <sup>3</sup> (2X_Q Output)	Output Pulse Width (2X_Q Output @ V <sub>CC</sub> /2)	0.5t <sub>CYCLE</sub> - 1.0	0.5tCYCLE + 1.0	ns
tpD 3		(470kΩ From F	C1 to An.V <sub>CC</sub> )	
(Sync-Feedback)	SYNC input to feedback delay	-1.05	-0.50	
	(meas. @ SYNC0 or 1 and FEEDBACK input pins)	(470kΩ From RC1 to An.GND)		ns
	(See General AC Specification note 4 and Fig. 2 for explanation)	+1.25	+3.25	
tskewr 1,3 (Rising)	Output-to-Output Skew Between Outputs Q0 - Q4, Q/2 (Rising Edges Only)	_	500	ps
tSKEWf 1,3 (Falling)	Output-to-Output Skew Between Outputs Q0 - Q4 (Falling Edges Only)	-	750	ps
tSKEWall 1,3	Output-to-Output Skew Between Outputs 2X_Q, Q/2, Q0 - Q4 Rising, Q5 Falling	_	750	ps
†LOCK	Time Required to acquire $^{2}$ Phase–Lock from time SYNC Input Signal is Received.	1	10	ms
tPHL (Reset – Q)	Propagation Delay, RST to Any Output (High-Low)	1.5	13.5	ns

## **RESET TIMING REQUIREMENTS 1**

Symbol	Parameter	Minimum	Unit
t <sub>REC</sub> , RST to SYNC	Reset Recovery Time rising RST edge to falling SYNC edge	9.0	ns
tw, RST LOW	Minimum Pulse Width, RST input LOW	5.0	ns

<sup>1.</sup> These reset specs are valid only when PLL\_EN is LOW and the part is in Test mode (not in phase-lock)

<sup>1.</sup> Under equally loaded conditions, C<sub>L</sub> ≤50pF (±2pF), and at a fixed temperature and voltage.
2. With V<sub>CC</sub> fully powered–on and an output properly connected to the FEEDBACK pin. t<sub>LOCK</sub> Max. is with C1 = 0.1μF, t<sub>LOCK</sub> Min is with C1 = 0.01μF.

<sup>3.</sup> These specifications are not tested, they are guaranteed by statistical characterization. See General AC Specification note 1.

### General AC Specification Notes

- 1. Several specifications can only be measured when the MC88915 is in phase-locked operation. It is not possible to have the part in phase-lock on ATE (automated test equipment). Statistical characterization techniques were used to guarantee those specifications which cannot be measured on the ATE. MC88915 units were fabricated with key transistor properties intentionally varied to create a 14 cell designed experimental matrix. IC performance was characterized over a range of transistor properties (represented by the 14 cells) in excess of the expected process variation of the wafer fabrication area. Response Surface Modeling (RSM) techniques were used to relate IC performance to the CMOS transistor properties over operation voltage and temperature. IC Performance to each specification and fab variation were used in conjunction with Yield Surface Modeling™ (YSM [M] methodology to set performance limits of ATE testable specifications within those which are to be guaranteed by
- statistical characterization. In this way all units passing the ATE test will meet or exceed the non-tested specifications limits.
- These two specs (tRISE/FALL and tPULSE Width 2X\_Q output) guarantee that the MC88915 meets the 25 MHz 68040 P-Clock input specification (at 50 MHz). For these two specs to be guaranteed by Motorola, the termination scheme shown below in Figure 1 must be used.
- 3. The wiring Diagrams and written explanations in Figure 5 demonstrate the input and output frequency relationships for three possible feedback configurations. The allowable SYNC input range for each case is also indicated. There are two allowable SYNC frequency ranges, depending whether FREQ\_SEL is high or low. Although not shown, it is possible to feed back the Q5 output, thus creating a 180° phase shift between the SYNC input and the "Q" outputs. Table 1 below summarizes the allowable SYNC frequency range for each possible configuration.

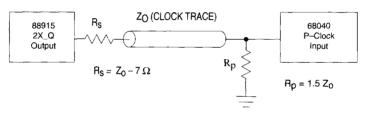


Figure 1. MC68040 P-Clock Input Termination Scheme

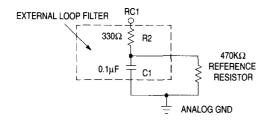
FREQ_SEL Level	Feedback Output	Allowable SYNC Input Frequency Range (MHZ)	Corresponding VCO Frequency Range	Phase Relationships of the "Q" Outputs to Rising SYNC Edge
HIGH	Q/2	5 to (2X_Q FMAX Spec)/4	20 to (2X_Q FMAX Spec)	0°
HIGH	Any "Q" (Q0-Q4)	10 to (2X_Q FMAX Spec)/2	20 to (2X_Q FMAX Spec)	0°
HIGH	Q5	10 to (2X_Q FMAX Spec)/2	20 to (2X_Q FMAX Spec)	180°
HIGH	2X_Q	20 to (2X_Q FMAX Spec)	20 to (2X_Q FMAX Spec)	<b>0</b> °
LOW	Q/2	2.5 to (2X_Q FMAX Spec)/8	20 to (2X_Q FMAX Spec)	0°
LOW	Any "Q" (Q0-Q4)	5 to (2X_Q FMAX Spec)/4	20 to (2X_Q FMAX Spec)	0°
LOW	Q5	5 to (2X_Q FMAX Spec)/4	20 to (2X_Q FMAXSpec)	180°
LOW	2X_Q	10 to (2X_Q FMAX Spec)/2	20 to (2X_Q FMAXSpec)	O <sub>2</sub>

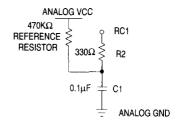
Table 1. Allowable SYNC Input Frequency Ranges for Different Feedback Configurations.

4. A 1 MΩ resistor tied to either Analog V<sub>CC</sub> or Analog GND as shown in Figure 2 is required to ensure no jitter is present on the MC88915 outputs. This technique causes a phase offset between the SYNC input and the output connected to the FEEDBACK input, measured at the input pins. The tpD spec describes how this offset varies with process, temperature, and voltage. The specs were arrived at by measuring the phase relationship for the 14

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lots described in note 1 while the part was in phase–locked operation. The actual measurements were made with a 10 MHz SYNC input (1.0 ns edge rate from 0.8 V - 2.0 V) with the Q/2 output fed back. The phase measurements were made at 1.5 V. The Q/2 output was terminated at the FEEDBACK input with 100  $\Omega$  to ground.





With the  $470 K\Omega$  resistor tied in this fashion, the tpD specification measured at the input pins is:

tpD = 2.25ns ± 1.0ns



With the  $470 K\Omega$  resistor tied in this fashion, the  $tp_D$  specification measured at the input pins is:

$$t_{PD} = -0.775 \text{ns} \pm 0.275 \text{ns}$$



Figure 2. Depiction of the Fixed SYNC to Feedback Offset (tPD) Which is Present When a  $470 \mathrm{K}\Omega$  Resistor is Tied to VCC or Ground

5. ThetsKEWrspecification guarantees that the rising edges of outputs Q/2, Q0, Q1, Q2, Q3, and Q4 will always fall within a 500ps window within one part. However, if the relative position of each output within this window is not specified, the 500 ps window must be added to each side of the tPD specification limits to calculate the total part-to-part skew. For this reason the absolute

distribution of these outputs are provided in table 2. When taking the skew data, Q0 was used as a reference, so all measurements are relative to this output. The information in Table 2 is derived from measurements taken from the 14 process lots described in Note 1, over the temperature and voltage range.

Output	_ (ps)	+ (ps)
Q0	0	0
Q1	-72	40
Q2	-44	276
Q3	-40	255
Q4	-274	-34
Q/2	-16	250
2X_Q	-633	-35

Table 2. Relative Positions of Outputs Q/2, Q0-Q4, 2X\_Q, Within the 500ps tskew, Spec Window

 Calculation of Total Output-to-Skew between multiple parts (Part-to-Part skew)

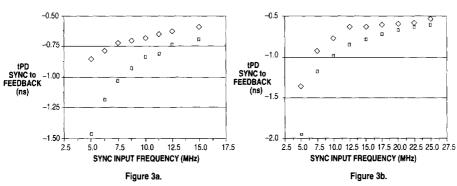
By combining the tpD specification and the information in Note 5, the worst case output—to—output skew between multiple 88915's connected in parallel can be calculated. This calculation assumes that all parts have a common SYNC input clock with equal delay of that input signal to each part. This skew value is valid at the 88915 output pins only (equally loaded), it does not include PCB trace delays due to varying loads.

With a 1M $\Omega$  resistor tied to analog V<sub>CC</sub> as shown in note 4, the tpp spec. limits between SYNC and the Q/2 output (connected to the FEEDBACK pin) are –1.05ns and –0.5ns. To calculate the skew of any given output between two or more parts, the absolute value of the distribution of that output given in table 2 must be subtracted and added to the lower and upper tpp spec limits respectively. For output Q2, [276 – (–44)] = 320ps is the absolute value of the distribution. Therefore [–1.05ns

-0.32ns] = -1.37ns is the lower tpp limit, and [-0.5ns + 0.32ns] = -0.18ns is the upper limit. Therefore the worst case skew of output Q2 between any number of parts is (-1.37) - (-0.18)l = 1.19ns. Q2 has the worst case skew distribution of any output, so 1.2ns is the absolute worst case output-to-output skew between multiple parts.

7. Note 4 explains that the tpD specification was measured and is guaranteed for the configuration of the Q/2 output connected to the FEEDBACK pin and the SYNC input running at 10MHz. The fixed offset (tpD) as described above has some dependence on the input frequency and at what frequency the VCO is running. The graphs of Figure 3 demonstrate this dependence.

The data presented in Figure 3 is from devices representing process extremes, and the measurements were also taken at the voltage extremes ( $V_{CC} = 5.25V$  and 4.75V). Therefore the data in Figure 3 is a realistic representation of the variation of tpp.



tpp versus Frequency Variation for Q/2 Output Fed Back, Including Process and Voltage Variation @ 25°C (With 1MΩ Resistor Tied to Analog V<sub>CC</sub>)

tpD versus Frequency Variation for Q4 Output Fed Back, Including Process and Voltage Variation @ 25°C (With 1MΩ Resistor Tied to Analog V<sub>CC</sub>)

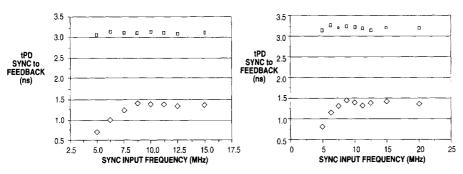


Figure 3c.

tpp versus Frequency Variation for Q/2 Output Fed Back, Including Process and Voltage Variation @ 25°C (With 1MΩ Resistor Tied to Analog GND)

Figure 3d.

tpp versus Frequency Variation for Q4 Output Fed lack, Including Process and Voltage Variation @ 25°C (With 1MΩ Resistor Tied to Analog GND)

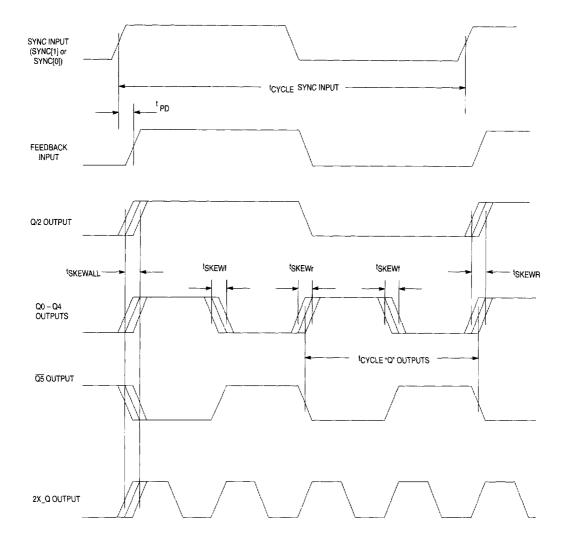


Figure 4. Output / Input Switching Waveforms and Timing Diagrams
(These waveforms represent the hook-up configuration of Figure 5a on page 164)

### **Timing Notes:**

- The MC88915 aligns rising edges of the FEEDBACK input and SYNC input, therefore the SYNC input does not require a 50% duty cycle.
- All skew specs are measured between the V<sub>CC</sub>/2 crossing point of the appropriate output edges. All skews
  are specified as 'windows', not as a ± deviation around a center point.
- If a "Q" output is connected to the FEEDBACK input (this situation is not shown), the "Q" output frequency
  would match the SYNC input frequency, the 2X\_Q output would run at twice the SYNC frequency, and the
  Q/2 output would run at half the SYNC frequency.

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:E

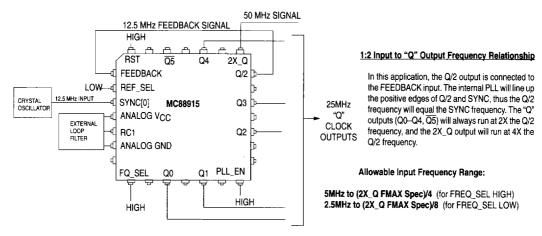


Figure 5a. Wiring Diagram and Frequency Relationships With Q/2 Output Feed Back

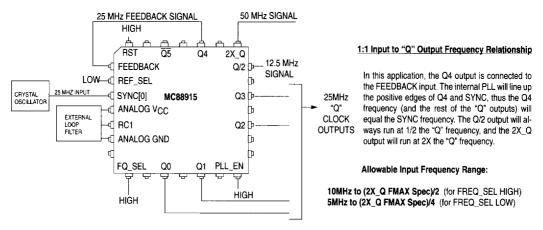


Figure 5b. Wiring Diagram and Frequency Relationships With Q4 Output Feed Back

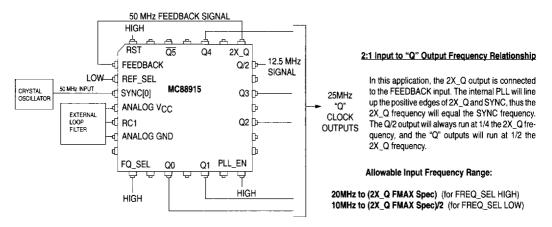


Figure 5c. Wiring Diagram and Frequency Relationships with 2X\_Q Output Feed Back

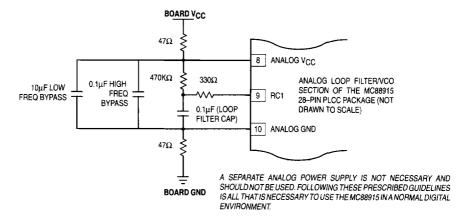


Figure 6. Recommended Loop Filter and Analog isolation Scheme for the MC88915

#### Notes Concerning Loop Filter and Board Layout Issues

- Figure 6 shows a loop filter and analog isolation scheme which will be effective in most applications. The following guidelines should be followed to ensure stable and jitter-free operation:
- 1a. All loop filter and analog isolation components should be tied as close to the package as possible. Stray current passing through the parasitics of long traces can cause undesirable voltage transients at the RC1 pin.
- 1b.The  $47\Omega$  resistors, the  $10\mu F$  low frequency bypass capacitor, and the  $0.1\mu F$  high frequency bypass capacitor form a wide bandwidth filter that will minimize the 88915's sensitivity to voltage transients from the system digital VCC supply and ground planes. This filter will typically ensure that a 100mV step deviation on the digital VCC supply will cause no more than a 100pS phase deviation on the 88915 outputs. A 250mV step deviation on VCC using the recommended filter values should cause no more than a 250pS phase deviation; if a 25 $\mu F$  bypass capacitor is used (instead of  $10\mu F$ ) a 250mV VCC step should cause no more than a 100pS phase deviation.

If good bypass techniques are used on a board design near components which may cause digital V<sub>CC</sub> and ground noise, the above described V<sub>CC</sub> step deviations should not occur at the 88915's digital V<sub>CC</sub> supply. The purpose of the bypass filtering scheme shown in Figure 6

- is to give the 88915 additional protection from the power supply and ground plane transients that can occur in a high frequency, high speed digital system.
- 1c.There are no special requirements set forth for the loop filter resistors (470K and  $330\Omega$ ). The loop filter capacitor (0.1 $\mu$ F) can be a ceramic chip capacitior, the same as a standard bypass capacitor.
- 1d.The 470K reference resistor injects current into the internal charge pump of the PLL, causing a fixed offset between the outputs and the SYNC input. This also prevents excessive jitter caused by inherent PLL dead-band. If the VCO (2X\_Q output) is running above 40MHz, the 470K resistor provides the correct amount of current injection into the charge pump (2–3μA). If the VCO is running below 40MHz, a 1MΩ reference resistor should be used (instead of 470K).
- 2. In addition to the bypass capacitors used in the analog filter of Figure 6, there should be a 0.1μF bypass capacitor between each of the other (digital) four V<sub>CC</sub> pins and the board ground plane. This will reduce output switching noise caused by the 88915 outputs, in addition to reducing potential for noise in the 'analog' section of the chip. These bypass capacitors should also be tied as close to the 88915 package as possible.

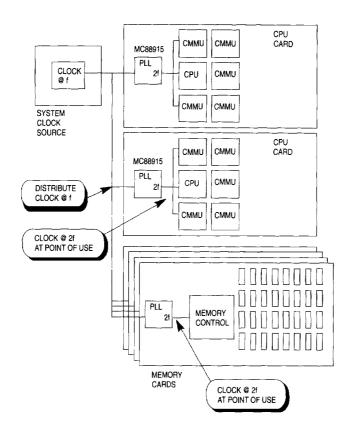


Figure 7. Representation of a Potential Multi-Processing Application Utilizing the MC88915 for Frequency Multiplication and Low Board-to-Board Skew

### MC88915 System Level Testing Functionality

When the PLL\_EN pin is low, the VCO is disabled and the 88915 is in low frequency "test mode". In test mode (with FREQ\_SEL high), the 2X\_Q output is inverted from the selected SYNC input, and the "Q" outputs are divide—by—2 (negative edge triggered) of the SYNC input, and the Q/2 output is divide—by—4. With FREQ\_SEL low the 2X\_Q output is divide—by—2 of the SYNC, the "Q" outputs divide—by—4, and the Q/2 output divide—by—8. These relationships can be seen on the block diagram. A recommended test configuration would be to use SYNCO as the test clock input, and the PLL\_EN and REF\_SEL together and connect them to the test select logic. When these inputs are low, the 88915 is in test mode and the SYNCO input is selected.

This functionality is needed since most board–level testers run at 1 MHz or below, and the 88915 cannot lock onto that low of an input frequency. In the test mode described above, any frequency test signal can be used.